Chinastandards.org

ICS 31.200
CCS L56

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ 21495-2018

Microelectronic packaging shell packaging technology requirements

微电子封装外壳 包装工艺技术要求

(English Translation)

Implemented on: March 1, 2019

Issued by: Ministry of Industry and Information Technology

Preview: page 1 of 3 shown, 8 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21495-2018

Chinastandards.org

Table of Contents

[Preview only]
1 Scope
2 Normative References
2.1 Terms
3 Terms and Definitions
4 Overview
4.1 General requirements
5 Technical Requirements
6 Calibration conditions
6.1 Environmental conditions
6.2 Measurement standards and other equipment
7 Calibration items and calibration methods
7.1 Calibration Items
7.2 Calibration method
8 Expression of calibration results
9 Recalibration interval

1 Foreword

SJ 21495-2018 is issued by Ministry of Industry and Information Technology.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

The document runs to 8 pages in English translation.

2 Scope Preview

SJ 21495-2018 falls under ICS 31.200, in the field of electronics.

This catalogue holds 133 other SJ standards in that field.

In this catalogue, SJ standards carry edition years from 1965 to 2021.

Preview: page 2 of 3 shown, 8 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21495-2018

3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 8 pages (approximate)

Chinese original: about 10,133 characters

4 Related standards

Standards on related subjects:

SJ/T 11890-2023 - Design requirement of energy conservation for LED displays

SJ/T 11891-2023 - Energy efficiency measurement method for LED displays

GB/T 35010.6-2018 - Semiconductor die products -- Part 6: Requirements for concerning thermal simulation

SJ 21634-2021 - Semiconductor integrated circuits - Multi-node low-voltage differential signaling (M-LVDS) test methods

SJ 21619-2021 - DC input passive EMI filter test method

SJ 21496-2018 - Technical requirements for gold plating process of microelectronic packaging shell

5 Classification and status

International classification (ICS): 31.200

Chinese Standard Classification (CCS): L 56

Prefix SJ: mandatory standard.

Preview: page 3 of 3 shown, 8 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21495-2018